

SEMICONDUCTOR TEST SOCKET HAVING POGO-PIN CONTACTS

ABSTRACT

A preferred embodiment test socket comprises a body for receiving a semiconductor device having a plurality of pins, the body having an integrally formed guidepost and a chamfered impact base and a floating base disposed within the body. The floating base coming into contact with the semiconductor device and provides movement of the semiconductor device to alleviate unwanted pressure from the plurality of pins. The test socket further comprises a plurality of pogo-pins adjacent to one another, each pogo-pin comprising a cylindrical chamber and a plunger having a crown top at both ends, one end for directly contacting a pin of the semiconductor device and the other end for contacting external test equipment and a back panel removably attached to the body.

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